

Notice of References Cited	Application/Control No. 10/568,805		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Claire L. Rademaker		Art Unit 1795	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0018926	02-2002	Shiga et al.	429/61
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	U	IPDL Machine Translation and Abstract in English of JP 09-022732.
	V	IPDL Machine Translation and Abstract in English of JP 2000-299107.
	W	IPDL Machine Translation and Abstract in English of JP 2003-142101.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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